

Amendments to the Claims: This listing of claims will replace all prior versions, and listings, of claims in the application

Listing of Claims:

1. (Canceled)
2. (Canceled)
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41. (Canceled)

42. (Canceled)

43. (Currently Amended) A method of docking a test head to a peripheral,
~~said method comprising the steps of:~~ according to claim 71,

wherein step a) is preceded by the step of a)——moving said test head
towards said peripheral;

b) ~~inserting docking members~~ said docking pin is coupled to said test
head ~~into and said pin receptacles~~ receptacle is coupled to said peripheral;

~~e) — moving said pin receptacles so that said docking members are pulled further into said pin receptacles in order to and~~ step b) includes the step of docking said test head and said peripheral.

44. (Original) A method of docking a test head to a peripheral according to claim 43, wherein one of said docking members includes a cam follower, and step c) includes the step of sliding said pin receptacle so that said cam follower moves along a groove in said pin receptacle in order to dock said test head and said peripheral.

45. (Original) The method of claim 44, wherein said pin receptacle slides under power.

46. (Original) The method of claim 44, wherein movement of a piston causes said pin receptacle to slide.

47. (Original) The method of claim 44, wherein said pin receptacle slides as a result of rotation of an arm.

48. (Original) The method of claim 44, wherein force is applied to one end of an arm which rotates about a pivot point so that another end of said arm slides said pin receptacle.

49. (Original) The method of claim 44, wherein said groove follows a path extending between sides of said pin receptacle with one end of said path deeper into said pin receptacle than another end of said path.

50. (Currently Amended) ~~A docking mechanism for docking a test head with a peripheral, comprising:~~ module according to claim 61

~~a first alignment feature and a~~ wherein said feature is graspable engagement element attached to one of the test head and the peripheral, and

wherein said movable feature receptacle is a docking module attached to the other of the test head and the peripheral said docking module, comprising:

- a) an alignment receptacle for receiving the alignment feature,
- b) a movable grasping member for receiving and grasping the graspable engagement element, said grasping member movable from a first position where the

graspable element is received to a second position where the ~~Graspable~~-graspable element (?) has been pulled, thus docking the test head and the peripheral,

c) a detector for detecting when the graspable element is in a position to be grasped,

d) an actuator for moving the movable grasping member in order to move the graspable element from a first position to a second position in order to dock said test head and said peripheral.

51. (Original) A docking mechanism according to claim 50, wherein movement of said graspable element from said first position to said second position is linear.

52. (Original) A docking mechanism according to claim 50 wherein movement of said grasping element is linear.

53. (Original) A docking mechanism according to claim 51 wherein the movement of said graspable element is substantially perpendicular to the movement of said grasping element.

54. (Original) A docking mechanism according to claim 52 wherein the movement of said graspable element is substantially perpendicular to the movement of said grasping element.

55. (Original) A docking mechanism according to claim 50, wherein said actuator is a linear actuator which moves along a linear path.

56. (Original) A docking mechanism according to claim 50, wherein said actuator is pneumatic.

57. (Original) A docking mechanism according to claim 50, wherein said actuator is an electrical solenoid.

58. (Original) A docking mechanism according to claim 50, wherein said graspable element is a cam follower and said grasping member includes a cam.

59. (Original) A docking mechanism according to claim 50, wherein said detector is one of a pneumatic switch and an electrical switch.

60. (Original) A docking mechanism according to claim 50, wherein said module is adjustable relative to said test head or said peripheral to which said module is mounted in an X, Y and Z direction.

61. (Original) A docking module comprising:

a feature detector for detecting a feature,

a movable feature receptacle; and

an actuator which, responsive to detection of said feature, moves a moveable feature of said moveable feature receptacle to capture said feature and pull said feature in a linear direction.

62. (Original) A docking module according to claim 61, wherein said docking module is one of a plurality of docking modules which are coupled to one of a test head and a peripheral, and said feature is one of a plurality of features coupled to the other of said test head and said peripheral, actuation of each actuator causes said test head to be docked to said peripheral.

63. (Original) A docking module according to claim 61, wherein said actuator is a linear actuator

64. (Original) A docking module according to claim 61, wherein said actuator is pneumatic.

65. (Original) A docking module according to claim 61, wherein said actuator is an electrical solenoid.

66. (Original) A docking module according to claim 61, wherein said moveable feature moves perpendicular to said linear direction.

67. (Original) A docking module according to claim 61, wherein said module feature is moved along a linear path.

68. (Original) A docking module according to claim 61, wherein said feature is a cam follower and said moveable feature receptacle includes a cam.

69. (Original) A docking module according to claim 61, wherein said feature detector is one of a pneumatic switch and an electrical switch.

70. (Original) A docking module according to claim 62, wherein said module is adjustable relative to said one of said test head and said peripheral in an X, Y and Z direction.

71. (Currently Amended) A method of docking ~~a test head to a peripheral, comprising the steps of:~~according to claim 85, wherein said feature is a docking pin and said moveable feature receptacle is a pin receptacle, said method further comprising the step of

inserting a said docking pin coupled to said a test head into a said pin receptacle coupled to said a peripheral, said docking pin including a cam follower situated on at least one side of said docking pin; and step b) includes the

step of said moveable feature which is part of said sliding said pin receptacle so that said cam follower moves along a groove in said pin receptacle in order to move said test head towards said peripheral.

72. (Original) The method of claim 71, wherein said pin receptacle slides under power.

73. (Original) The method of claim 71, wherein movement of a piston causes said pin receptacle to slide.

74. (Original) The method of claim 71, wherein said pin receptacle slides as a result of rotation of an arm.

75. (Original) The method of claim 71, wherein force is applied to one end of an arm which rotates about a pivot point so that another end of said arm slides said pin receptacle.

76. (Original) The method of claim 71, wherein said groove follows a path extending between sides of said pin receptacle with one end of said path deeper into said pin receptacle than another end of said path.

77. (Original) A method of docking a test head to a peripheral, said method comprising the steps of:

a) actuating a driving unit coupled to the test head to push the test head towards the peripheral;

b) actuating a further driving unit coupled to one of the test head and the peripheral to pull the test head towards the peripheral;

wherein step a) and step b) overlap for a period of time.

78. (Original) A method of docking a test head to a peripheral according to claim 77, wherein step b) is initiated responsive to said test head being in a predetermined position while step a) is being performed.

79. (Original) A method of docking a test head to a peripheral according to claim 78, wherein, in said predetermined position, docking members coupled to one of the test head and the peripheral are aligned with pin receptacles coupled to the other of the test head and the peripheral.

80. (Original) A method of docking a test head to a peripheral according to claim 79, wherein in said predetermined position, said docking members are in said pin receptacles.

81. (Original) A method of docking a test head to a peripheral according to claim 77, wherein at the end of said period of time, actuating of said driving unit is terminated.

82. (Original) A method of docking a test head to a peripheral according to claim 77, wherein at the end of said period of time, brakes applied to said driving unit are released.

83. (Original) A method of docking a test head to a peripheral according to claim 77, further comprising the step of mating respective electrical contacts on said test head and said peripheral after step b) has been initiated.

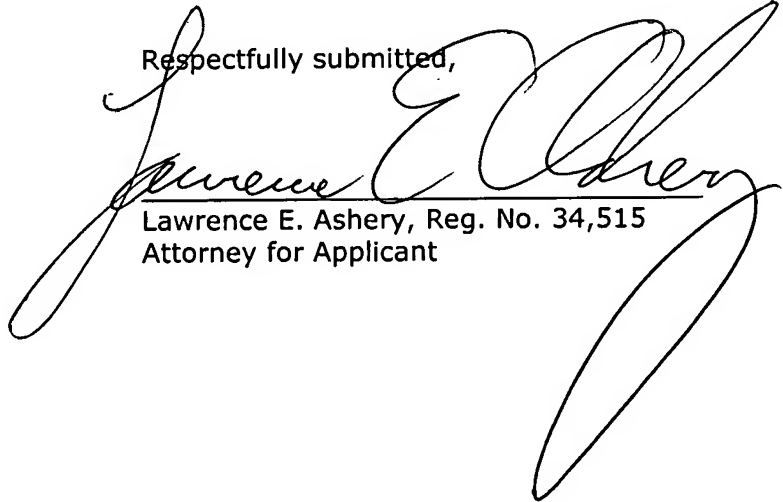
84. (Original) A method of docking a test head to a peripheral according to claim 77, wherein brakes are applied to said driving unit prior to performing step b).

85. (New) A method of docking,
said method comprising the steps of:

a) detecting a feature using a feature detector;

b) actuating an actuator, responsive to detection of said feature, in order to move a moveable feature of a moveable feature receptacle in order to capture said feature and pull said feature in a linear direction.

Respectfully submitted,



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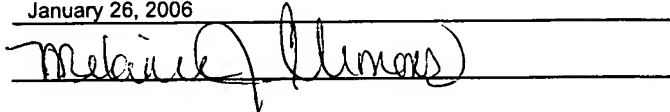
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